

Silicon Carbide Schottky Diode

FEATURES:

- Worlds first 600V Schottky diode
- Revolutionary semiconductor material -Silicon Carbide
- Switching behavior benchmark
- No reverse recovery
- No temperature influence on the switching behavior
- Ideal diode for Power Factor Correction
- No forward recovery

Applications:

• SMPS, PFC, snubber



Chip Type	V _{BR}	l _F	Die Size	Package	Ordering Code
SIDC11D60SIC3	600V	4A	1.15 x 0.97 mm ²	sawn on foil	Q67050-A4161- A104

MECHANICAL PARAMETER:

1.15 x 0.97				
0.85 x 0.67	mm			
1.116 / 0.581	mm ²			
355	μm			
75	mm			
0	deg			
3555 pcs				
Photoimide				
3200 nm Al				
1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding				
electrically conductive glue or solder				
Wire bond $AI, \le 250 \mu m$				
Ø ≥ 0.3 mm				
store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				
	0.85×0.67 $1.116 / 0.581$ 355 75 0 0 3555 pcs Photoimide 3200 nm Al $1400 \text{ nm Ni Ag -system}$ suitable for epoxy and soft solder dieelectrically conductive glue or set $Al, \leq 250 \mu m$ $\emptyset \geq 0.3 \text{ mm}$ store in original container, in dry n			



Maximum Ratings

Parameter	Symbol	Condition	Value	Unit	
Repetitive peak reverse voltage	V _{RRM}		600	V	
Surge peak reverse voltage	V _{RSM}		600	~	
Continuous forward current limited by T _{jmax}	I _F		4		
Single pulse forward current (depending on wire bond configuration)	I _{FSM}	$T_C = 25^{\circ}C, t_P = 10 \text{ ms sinusoidal}$	12.5	А	
Maximum repetitive forward current limited by T _{jmax}	I _{FRM}	$T_C = 100^{\circ}C, \ T_j = 150^{\circ}C, \ D=0.1$	18		
Non repetitive peak forward current	I _{FMAX}	$T_C = 25^\circ C, tp = 10 \mu s$	40	7	
Operating junction and storage temperature	$T_{\rm j}$, $T_{\rm stg}$		-55+175	°C	

Static Electrical Characteristics (tested on chip), T_j =25 °C, unless otherwise specified

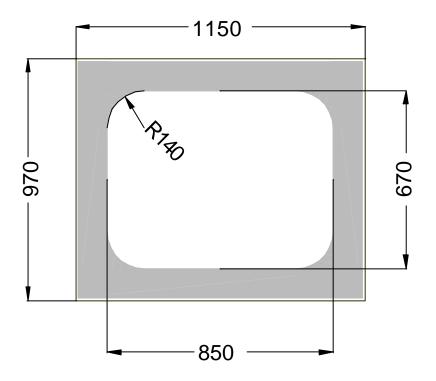
Parameter	Symbol	Cond	itiono		Value	Unit		
Falameter	Symbol	Cond	nions	min.	Тур.	max. 5 200	Onit	
Reverse leakage current	I _R	V _R =600V	<i>T_j</i> =25 ° <i>C</i>		15	200	μΑ	
Forward voltage drop	V _F	I _F =4A	<i>T_j</i> =25°C		1.7	1.9	V	

Dynamic Electrical Characteristics, at T_j = 25 °C, unless otherwise specified, tested at component

Parameter	Symbol	Conditions		Value			Unit
Falameter	Symbol			min.	Тур.	max.	
Total capacitive charge	Q _C	$I_F=4A$ di/dt=200A/ms $V_R=400V$	$T_j = 150 \ ^\circ C$		13		nC
Switching time	t _{rr}	$I_{F}=4A$ di/dt=200A/ms $V_{R}=400V$	$T_j = 150 \ ^\circ C$		n.a.		ns
Total capacitance C	С	$I_{F}=4A$ di/dt=200A/ms $T_{j}=25^{\circ}C$ f=1MHz	$V_R = 1 V$		150		
			V _R =300V		10		pF
			V _R =600V		7		



CHIP DRAWING:





FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

INFINEON TECHNOLOGIES

SDP04S60

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

Published by Infineon Technologies AG Bereich Kommunikation St.-Martin-Strasse 53 D-81541 München © Infineon Technologies AG 2000 All Rights Reserved.

Attention please!

The information herein is given to describe certain components and shall not be considered as warranted characteristics.

Terms of delivery and rights to technical change reserved.

We hereby disclaim any and all warranties, including but not limited to warranties of non-infringement, regarding circuits, descriptions and charts stated herein.

Infineon Technologies is an approved CECC manufacturer.

Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office in Germany or our Infineon Technologies Representatives world-wide (see address list).

Warnings

Due to technical requirements components may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies Office.

Infineon Technologies components may only be used in life-support devices or systems with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body, or to support and / or maintain and sustain and / or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.

单击下面可查看定价,库存,交付和生命周期等信息

>>Infineon(英飞凌)